


<b>Search Notes</b> 	<b>Application/Control No.</b> 10568392	<b>Applicant(s)/Patent Under Reexamination</b> MIHARA ET AL.
	<b>Examiner</b> Chang-Yu Wang	<b>Art Unit</b> 1649

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Sequence search: SEQ ID NO:1 regular and oligomer search. See search results in SCORE (7/1/08).	9/2/08	CYW
EAST, STN: search strategy attached	9/2/08	CYW
Inventor name search: EAST, STN, PALM	9/2/08	CYW
PLUS search from STIC. See search results in eDAN (7/1/08).	9/2/08	CYW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/C. Y.W./  
Examiner, Art Unit 1649